

#### **General Description**

The WSD3023DN56 is the highest performance trench N-ch and P-ch MOSFETs with extreme high cell density, which provide excellent RDSON and gate charge for most of the synchronous buck converter applications.

The WSD3023DN56 meet the RoHS and Green Product requirement 100% EAS guaranteed with full function reliability approved.

#### **Features**

- Advanced high cell density Trench technology
- Super Low Gate Charge
- Excellent CdV/dt effect decline
- 100% EAS Guaranteed
- Green Device Available

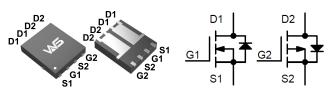
## **Product Summery**

BVDSS	RDSON	ID
30V	14mΩ	14A
-30V	23mΩ	-12A

## **Applications**

- High Frequency Point-of-Load Synchronous Buck Converter for MB/NB/UMPC/VGA
- Networking DC-DC Power System
- CCFL Back-light Inverter

#### **DFN5X6C-8-EP2 Pin Configuration**



# **Absolute Maximum Ratings**

		Rati		
Symbol	Parameter	N-Ch	P-Ch	Units
$V_{DS}$	Drain-Source Voltage	30	-30	V
$V_{GS}$	Gate-Source Voltage	±20	±20	V
	Continuous Drain Current, V <sub>GS(NP)</sub> =10V,T <sub>a</sub> =25 C	14*	-12	А
I <sub>D</sub>	Continuous Drain Current, V <sub>GS(NP)</sub> =10V,T <sub>a</sub> =70 ℃	7.6	-9.7	А
I <sub>DP</sub> <sup>a</sup>	Pulse Drain Current Tested, V <sub>GS(NP)</sub> =10V	488	-48	А
E <sub>AS</sub> c	Avalanche Energy, Single pulse , L=0.5mH	20	20	mJ
l <sub>AS</sub> c	Avalanche Current, Single pulse , L=0.5mH	9	-9	А
P <sub>D</sub>	Total Power Dissipation, T <sub>a</sub> =25 °C	5.25	5.25	W
T <sub>STG</sub>	Storage Temperature Range	-55 to 175	-55 to 175	$^{\circ}$
TJ	Operating Junction Temperature Range	175	175	°C
R <sub>eJA</sub> b	Thermal Resistance-Junction to Ambient, Steady State	60	60	°C/W
$R_{ heta JC}$	Thermal Resistance-Junction to Case, Steady State	6.25	6.25	°C/W

Note \*: Max. current is limited by bonding wire.

Note a: Pulse width limited by max. junction temperature.

Note  $b: R_{\theta,JA}$  steady state t=999s.  $R_{\theta,JA}$  is measured with the device mounted on  $1in^2$ , FR-4 board with 2oz. Copper. Note c: UIS tested and pulse width limited by maximum junction temperature  $175^{\circ}C$  (initial temperature  $T_i=25^{\circ}C$ ).



# Electrical Characteristics (T<sub>J</sub>=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =250uA	30			V
D d	Static Drain-Source On-Resistance	$V_{GS}$ =10V , $I_D$ =8A		14	18.5	mΩ
$R_{DS(ON)}^{d}$		V <sub>GS</sub> =4.5V , I <sub>D</sub> =5A		17	25	
$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS}=V_{DS}$ , $I_D=250uA$	1.3	1.8	2.3	٧
I	Danier Courses Londons Courses	$V_{DS}$ =20V , $V_{GS}$ =0V , $T_{J}$ =25 $^{\circ}$ C			1	uA
I <sub>DSS</sub>	Drain-Source Leakage Current	$V_{DS}$ =20V , $V_{GS}$ =0V , $T_{J}$ =85 $^{\circ}$ C			30	
I <sub>GSS</sub>	Gate-Source Leakage Current	$V_{GS}=\pm 20V$ , $V_{DS}$ =0V			±100	nA
$R_g$	Gate Resistance	V <sub>DS</sub> =0V , V <sub>GS</sub> =0V , f=1MHz		1.7	3.4	Ω
Qge	Total Gate Charge	V <sub>DS</sub> =15V, V <sub>GS</sub> =4.5V, I <sub>DS</sub> =8A		5.2		
Q <sub>gs</sub> e	Gate-Source Charge			1.0		nC
Q <sub>gd</sub> e	Gate-Drain Charge			2.8		
T <sub>d(on)</sub> e	Turn-On Delay Time	V <sub>DD</sub> =15V,R <sub>L</sub> =15R, I <sub>DS</sub> =1A,V <sub>GEN</sub> =10V, R <sub>G</sub> =6R.		6		
T <sub>r</sub> e	Rise Time			8.6		20
T <sub>d(off)</sub> e	Turn-Off Delay Time			16		ns
T <sub>f</sub> e	Fall Time			3.6		
C <sub>iss</sub> e	Input Capacitance	V <sub>DS</sub> =15V , V <sub>GS</sub> =0V , f=1MHz		545		
C <sub>oss</sub> e	Output Capacitance			95		pF
C <sub>rss</sub> e	Reverse Transfer Capacitance			55		

## **Diode Characteristics**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
I <sub>S</sub>	Continuous Source Current	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			12	Α
$V_{SD}^d$	Diode Forward Voltage	$V_{GS}$ =0V , $I_{S}$ =1A , $T_{J}$ =25 $^{\circ}$ C			1.2	V

Note d : Pulse test ; pulse width  $\!\leq\!300\mu\text{s},$  duty cycle  $\!\leq\!2\%.$ 

Note e: Guaranteed by design, not subject to production testing.



# P-Channel Electrical Characteristics (T<sub>J</sub>=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =-250uA	-30			V
D d	Otatio Busin Oceano Oce Businia	V <sub>GS</sub> =-10V , I <sub>D</sub> =-12A		23	32.5	mΩ
$R_{DS(ON)}^d$	Static Drain-Source On-Resistance	V <sub>GS</sub> =-4.5V , I <sub>D</sub> =-5A		32	42	
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{GS}=V_{DS}$ , $I_D=-250uA$	-1.3	-1.8	-2.3	V
I <sub>DSS</sub>	Drain-Source Leakage Current	$V_{DS}$ =-20V , $V_{GS}$ =0V , $T_J$ =25 $^{\circ}$ C			-1	- uA
IDSS		$V_{DS}$ =-20V , $V_{GS}$ =0V , $T_J$ =85 $^{\circ}$ C			-30	
I <sub>GSS</sub>	Gate-Source Leakage Current	$V_{GS}=\pm 20V$ , $V_{DS}$ =0V			±100	nA
$Q_g^e$	Total Gate Charge			13		
Q <sub>gs</sub> e	Gate-Source Charge	$V_{DS}$ =-15V , $V_{GS}$ =-4.5V , $I_{D}$ =-12A		1.0		nC
Q <sub>gd</sub> e	Gate-Drain Charge			4.0		
T <sub>d(on)</sub> e	Turn-On Delay Time			8.7		
T <sub>r</sub> e	Rise Time	$V_{DD}$ =-15V , $V_{GS}$ =-10V , $R_G$ =6 $\Omega$ ,		10		no
T <sub>d(off)</sub> e	Turn-Off Delay Time	$I_D$ =-1A , $R_L$ =15 $\Omega$ ,		22		ns
T <sub>f</sub> e	Fall Time	1		9.0		
C <sub>iss</sub> e	Input Capacitance			580		
C <sub>oss</sub> e	Output Capacitance	V <sub>DS</sub> =-15V , V <sub>GS</sub> =0V , f=1MHz		105		pF
C <sub>rss</sub> e	Reverse Transfer Capacitance	]		72		

## **Diode Characteristics**

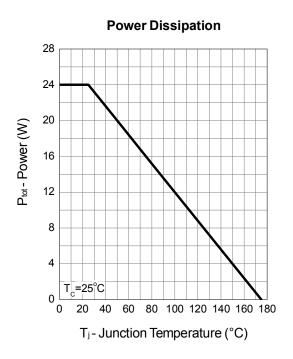
Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Is	Continuous Source Current	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			-10	Α
V <sub>SD</sub> e	Diode Forward Voltage	V <sub>GS</sub> =0V , I <sub>S</sub> =-1A , T <sub>J</sub> =25°C			-1.2	V

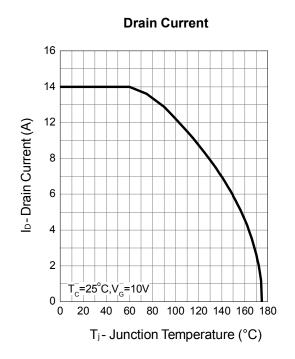
Note d : Pulse test; pulse width $\leq$ 300 $\mu$ s, duty cycle $\leq$ 2%.

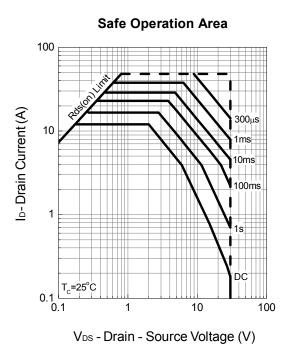
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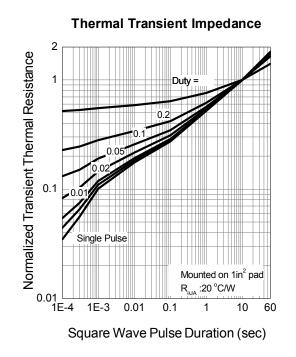


# **N-Channel Typical Characteristics**



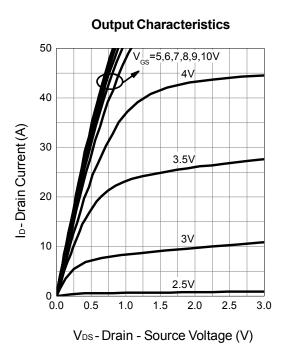


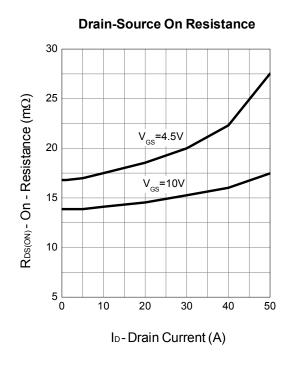


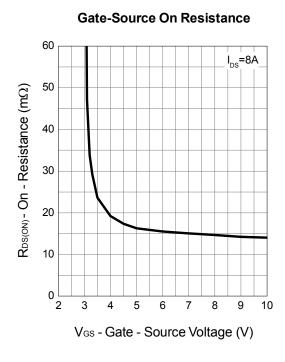


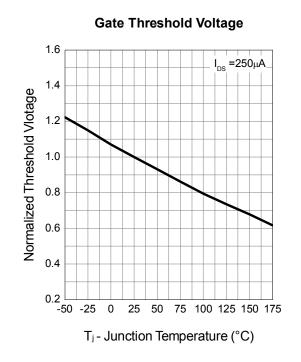


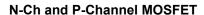
# **N-Channel Typical Characteristics**





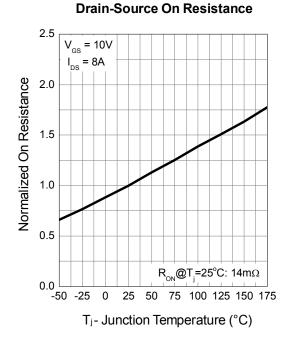




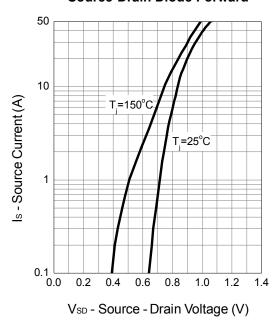




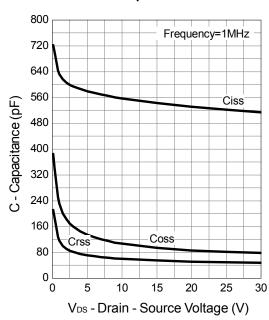
# **N-Channel Typical Characteristics**



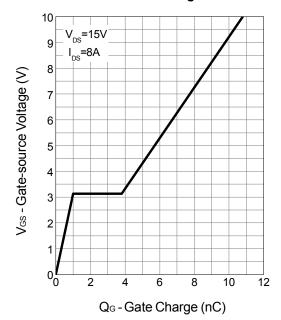
#### Source-Drain Diode Forward



## Capacitance

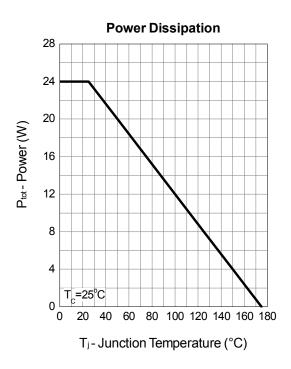


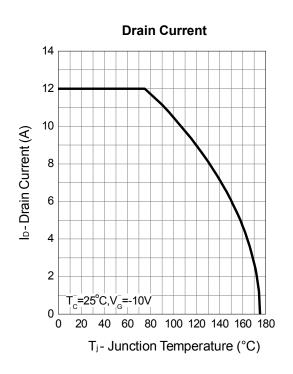
## **Gate Charge**

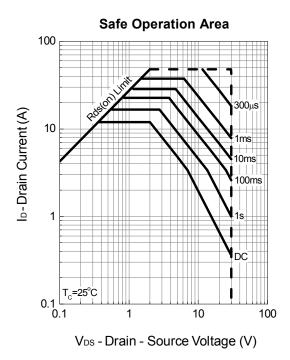


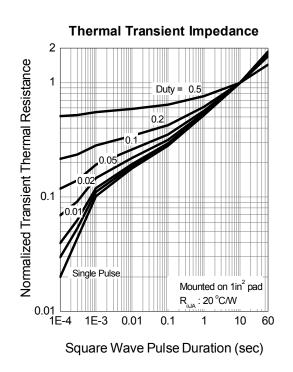


# **P-Channel Typical Characteristics**



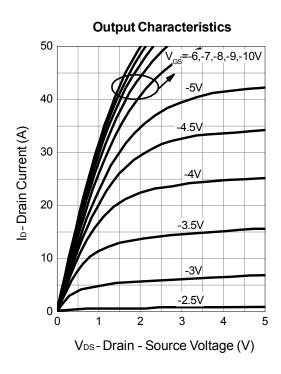


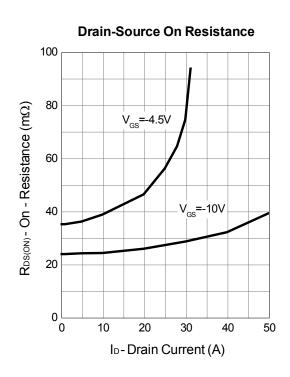


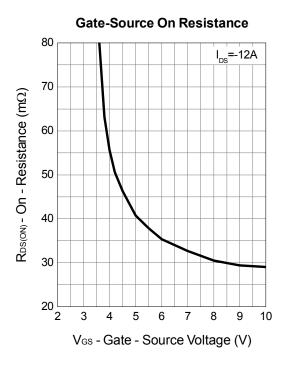


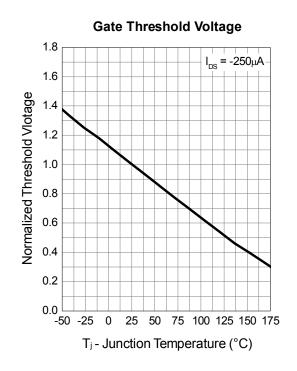


## **P-Channel Typical Characteristics**



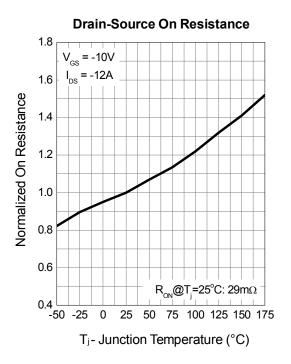


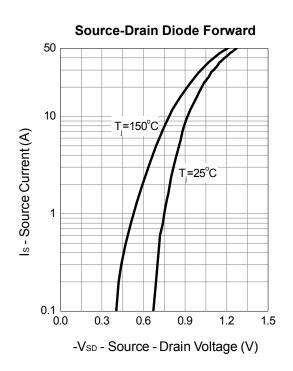


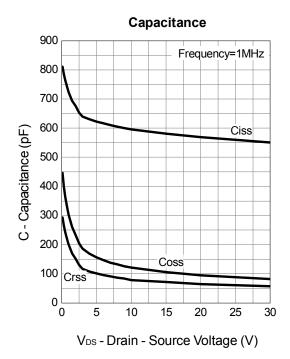


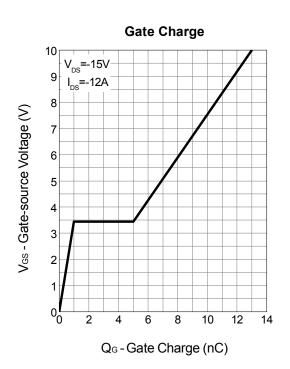


# **P-Channel Typical Characteristics**











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